

Towards high mobility in 2D electron gas in GaN/AlGaIn

H. Teisseyre¹, B. Damilano², Y. Cordier², Z. Adamus¹, T. Wojtowicz³, M. Boćkowski⁴



¹ Institute of Physics, Polish Academy of Sciences, Warsaw, Poland

² Université Côte d'Azur, CNRS, CRHEA, Valbonne, France

³ International Research Centre MagTop, Institute of Physics, Polish Academy of Sciences, Warsaw, Poland

⁴ Institute of High Pressure Physics, Polish Academy of Sciences, Warsaw, Poland

Close on the developments in nitride visible photonics during the 1990s was the discovery of a two-dimensional electron gas (2DEG) at nominally undoped AlGaIn/GaN heterojunctions.¹ The formation of these 2DEGs was found to result from the interplay of internal spontaneous and piezoelectric polarization fields combined with band offsets. Today, the Al(Ga)N/GaN heterojunction system, featuring a polarization-induced 2DEG and a large bandgap channel and barrier, is at the core of nitride-based high-electron mobility transistors (HEMTs).

PREVIOUS RESULTS

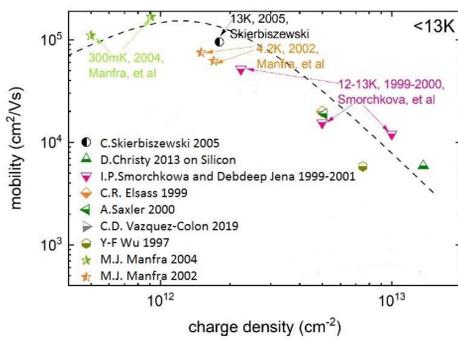


Fig. 1. Mobility versus 2DEG density relationship from different publications at low temperature

The ultrahigh mobility of 2DEG in AlGaIn/GaN system is useful for:

- High-speed, high-frequency electronics (5G, radar, satellite communications)
- High-power electronics
- Harsh-environment application (space, defense, aerospace)
- Sensor and radiation detectors
- Emerging fields like quantum computing and spintronics

In AlxGa1-xAs-based material systems, low-temperature electron mobility has reached values exceeding 100 million cm²/Vs [2]. In the ZnO/ZnMgO system, low-temperature electron mobility surpasses 1,000,000 cm²/Vs [3]. However, it remains unclear why the best results in GaN/AlGaIn systems achieve only a low-temperature electron mobility record of 167,000 cm²/Vs, as reported by Manfra et al. in 2004. [4]

by using a high-quality substrate, we aim to break this record!!!

HIGH QUALITY SUBSTRATE Ammonothermal-GaN

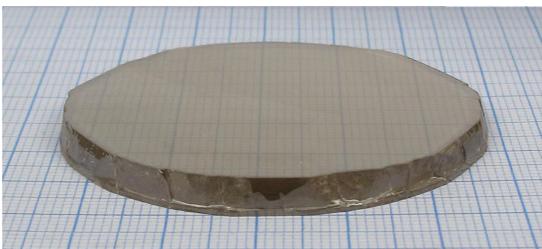


Fig. 2. Ammonothermal-GaN crystal grown in one crystallization run: 6-mm-thick and with a 2.1-inch diameter; grid 1 mm

Scheme of basic ammonothermal system

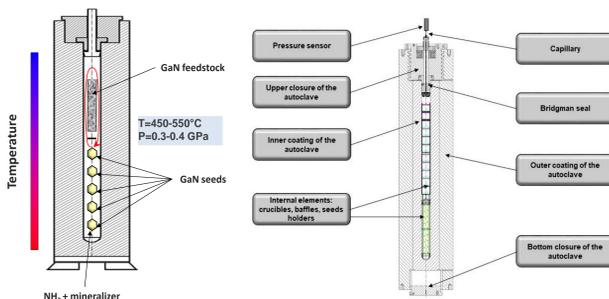


Fig. 3. a) Scheme of basic ammonothermal process and cross-section of autoclave divided into dissolution zone (with feedstock) and crystallization zone (with GaN seeds); red arrow symbolizes the convective mass transport in the temperature gradient; b) scheme of a typical ammonothermal autoclave used at IHPP PAS (Institute of High Pressure Physics Polish Academy of Sciences); the main elements are marked; all parts are made of high quality steel and high purity metals; crucibles with feedstock are in the upper zone of the autoclave; native seeds on special holders in the lower zone; the zones are divided by baffles.

as a substrates we used GaN highly doped with manganese!

HIGH QUALITY STRUCTURE GROWN BY AMMONIA MBE/ SQW GaN/AlGaIn example

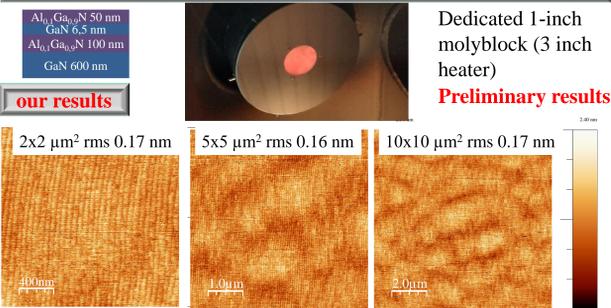


Fig. 4. Atomic force microscopy (AFM) results for 6nm single quantum well GaN/AlGaIn grown by the molecular-beam epitaxy on the ammonothermal substrates. In all measured magnifications RMS is constant and atomic steps are clearly visible.

COMPARISON PANCHROMATIC / SQW GaN/AlGaIn example

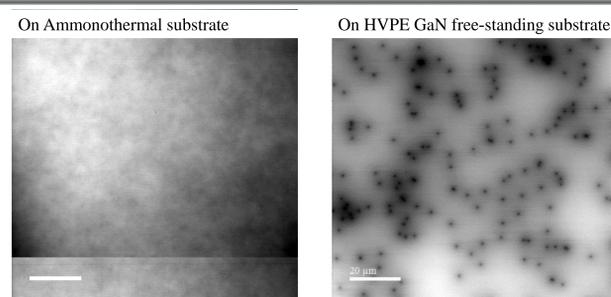


Fig. 5. Comparison of cathodoluminescence imaging measurements, for layers grown on the ammonothermal substrate (density of dark spots below 10⁴ cm⁻²) and layers grown on HVPE (Halide Vapor Phase Epitaxy) free-standing substrate (Dark spot density = 1,7x10⁶ cm⁻²).

SQW GaN/AlGaIn example / low temperature PL

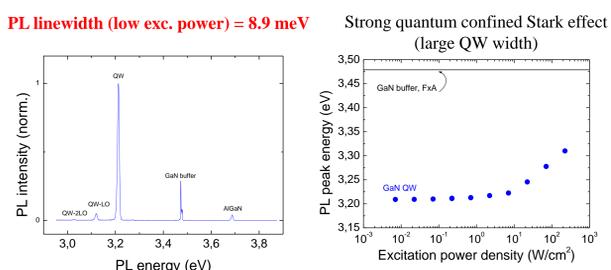
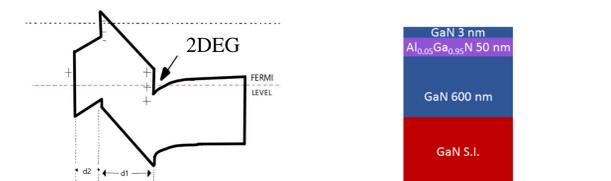


Fig. 6. Results of photoluminescence measurements for a single 6.5 nm quantum well grown on the ammonothermal substrate. Despite a strong built-in electric field (quantum confined Stark effect), full width at half maximum of emission related to the quantum well is very low 8.9 meV.

Polarization- induced 2D electron gas in nitrides

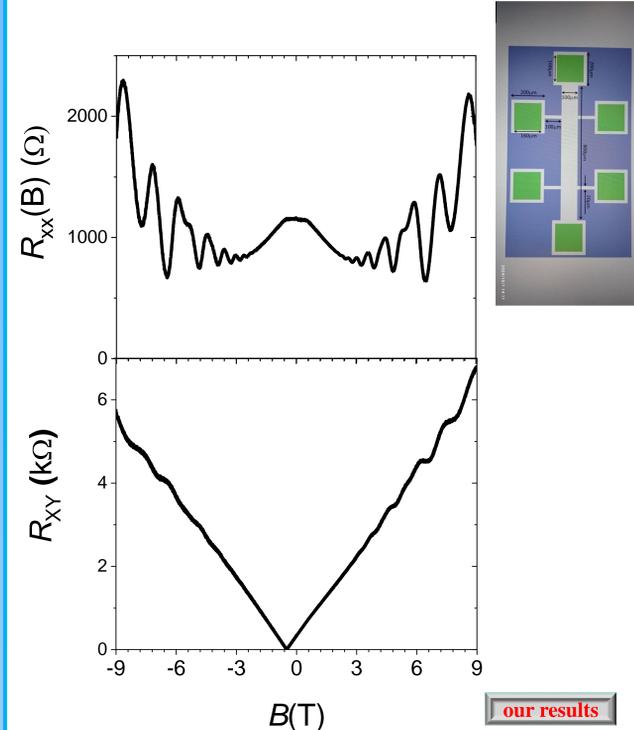


To achieve very high 2DEG mobility in AlGaIn/GaN systems, you need:

- High-quality epitaxial growth with minimal defects and impurities. (**High quality substrates, Ammonia MBE**)
- A smooth, abrupt GaN/AlGaIn interface with optimized barrier thickness and aluminum content. (**low aluminum concentration**)
- Careful control of scattering mechanisms (impurities, roughness, phonons). (**low temperature measurements**)
- Proper strain and thermal management to reduce defect densities and phonon scattering. (**low aluminum concentration, high quality substrates**)

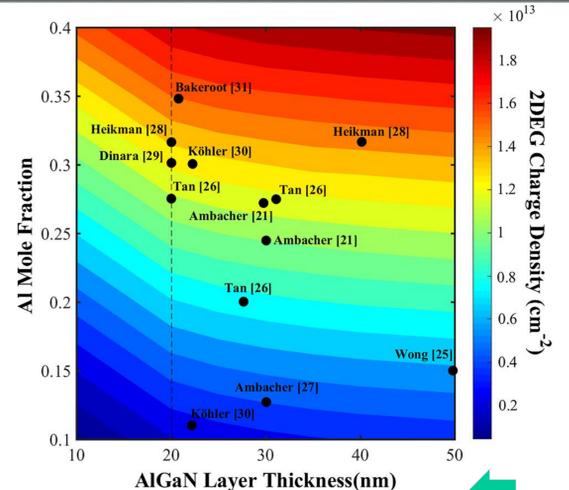
our results

GaN/AlGaIn 2DEGs IN THE QUANTUM REGIME



Magetotransport studies at T=3K indicate presence of 2DEG in the structure (Quantum Hall effect). Values of magnetic field where plateaus are seen give information about concentration of 2DEG $B_n = h n_{2D} / e n$ and resistance shows mobility of the carriers $\mu = (n_{2D} e \rho)^{-1}$; $n_{2D} = 9.4 \cdot 10^{13} \text{ cm}^{-2}$, $\mu = 25000 \text{ cm}^2/\text{Vs}$ Qualitative analysis of results proves the existence of the parasitic channel of conductance (parallel conductivity).

What should be the next step....



Manfra results (167.000 cm²/Vs) Our results (25.000 cm²/Vs)

Fig. 8. Contour plot of 2DEG charge density for GaN HEMT as a function of barrier layer thickness (d) and Al mole fraction in the barrier layer. Experimental data indicated by black (After Analytical Model for Two-Dimensional Electron Gas Charge Density in Recessed-Gate GaN High-Electron-Mobility Transistors by Samaneh Sharbati et al.)

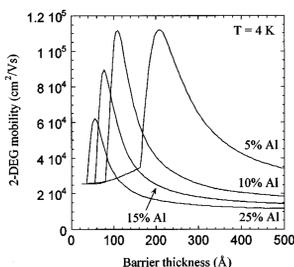


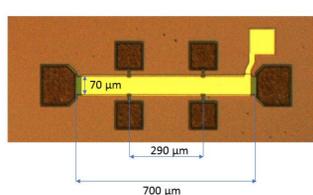
Fig. 9 Low temperature 2DEG mobilities as a function of barrier thickness for four different AlGaIn heterostructures with different Al barrier compositions.. (After Effect of polarization fields on transport properties in AlGaIn/GaN Heterostructures by L. Hsu and W. Walukiewicz.)

We should lowered the AlGaIn barrier thickness keeping low concentration of aluminum.

Conclusions



New sample is waiting for measurements to be continued



our results

References

1. M. A. Khan, J. N. Kuznia, J. M. Van Hove, N. Pan, and J. Carter, "Observation of a two-dimensional electron gas in low pressure metal organic chemical vapor deposited GaN-AlGaIn heterojunctions," Appl. Phys. Lett. 60, 3027 (1992).
2. Yoon Jang Chung, A. Gupta, K. W. Baldwin, K. W. West, M. Shayegan, and L. N. Pfeiffer Understanding limits to mobility in ultrahigh-mobility GaAs two-dimensional electron systems: 100 million cm²/Vs and beyond Phys. Rev. B 106, 075134 (2022)
3. J. Falson, Y. Kozuka, M. Uchida, J.H. Smet, T. Arima, A. Tsukazaki & M. Kawasaki "MgZnO/ZnO heterostructures with electron mobility exceeding 1 × 10⁶ cm²/Vs" Scientific Reports 6, 26598 (2016)
4. M. J. Manfra, K. W. Baldwin, A. M. Sergent, K. W. West, R. J. Molnar and J. Caissie Electron mobility exceeding 160 000 cm²/Vs in AlGaIn / GaN heterostructures grown by molecular-beam epitaxy Applied Physics Letters 85 p5394 (2004)
5. S. Sharbati, I. Gharibshabian, T. Ebel, A. A. Orouji, W.-T. Franke "Analytical Model for Two-Dimensional Electron Gas Charge Density in Recessed-Gate GaN High-Electron-Mobility Transistors" Journal of Electronic Materials (2021) 50:3923–3929
6. L. Hsu, W. Walukiewicz "Effect of polarization fields on transport properties in AlGaIn/GaN heterostructures" J. Appl. Phys. 89, 1783–1789 (2001)

Acknowledgment

This work was supported by the Polish National Science Centre within the OPUS Project No. 2020/37/B/ST8/03446